

Application No. 10/697,647
Amendment under 37 C.F.R. §1.111 dated January 19, 2005
Response to the Office Action of October 19, 2004

In the Specification

Please **DELETE** the Abstract of the Disclosure in its entirety and substitute therefor the following Abstract.

ABSTRACT

An electron beam apparatus including an electron gun for directing a plurality of primary electron beams onto a sample, an objective lens for forming an electric field to accelerate a plurality of secondary electron beams emitted from the sample, and a separator for separating the plurality of secondary electron beams from a primary optical system and for directing the plurality of secondary electron beams into a secondary optical system for guiding to a detector outputting a detection signal of the secondary electron beams. A deflector deflects the secondary electron beams in the secondary optical system. The deflector is controlled to deflect the plurality of secondary electron beams synchronously with scanning of the plurality of primary electron beams, thereby preventing the plurality of secondary electron beams from moving on the detector in response to the scanning of the plurality of primary electron beams.